

Application/Control No.	Applicant(s)/Patent under Reexamination		
09/924,054	SAITO, HIROYUKI		
Examiner	Art Unit		
John L. Shew	2616		

	SEARCHED		
Class	Subclass	Date	Examiner
340	2.1,2.23	6/23/2006	JS
	2.24,3.1		
370	229,230.1	6/23/2006	JS
	232,233		
	235,237		
	238,238.1		
	252,351		
	389,395.1		
_	395.21		
	395.32		
	395.41		
	400,468		
	477,537		
	538,540		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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(INCLUDING SEARC	CH STRATEGY	(INCLUDING SEARCH STRATEGY)		
	DATE	EXMR		
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Search	Notes	s (conti	nued)

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Class	Subclass	Date	Examiner
709	220,221	6/23/2006	JS
	222,225		
	226,238		_
	239		
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INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE EXM		